



IFW
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Toshiharu Furukawa et al. : Date: July 7, 2005
Group Art Unit: 2811 : IBM Corporation
Examiner: Unassigned : Intellectual Property Law
Serial No.: 10/767,039 : Dept. 917, Bldg. 006-1
Filed: January 29, 2004 : 3605 Highway 52 North
Title: VERTICAL FIELD EFFECT : Rochester, MN 55901
TRANSISTORS INCORPORATING
SEMICONDUCTING NANOTUBES
GROWN IN A SPACER-DEFINED
PASSAGE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

July 7, 2005

(Date of Deposit)

Debra A. Peterson

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INFORMATION DISCLOSURE STATEMENT


Applicants request that the information listed on the attached Form PTO/SB/08A be considered by the Office during the pendency of the above entitled application, pursuant to 37 C.F.R. 1.97. In accordance with 37 C.F.R. 1.97(h), the filing of this Information Disclosure Statement shall not constitute an admission that any information cited therein is, or is considered to be, material to patentability as defined in 37 C.F.R. 1.56(b). In the interest of full and complete disclosure to the Office, some or all of the art cited herein may not be considered by Applicant(s) or the Undersigned to be material under the new standard of materiality defined in 37 C.F.R. 1.56(b), enacted March 16, 1992, but may be material under the old standard of materiality defined in 37 C.F.R. 1.56(a), last amended on November 28, 1988, or may merely be technical background which may be of interest to the Examiner. In accordance with

37 C.F.R. 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made.

The references listed herein were cited in a search report by a foreign patent office, a copy of which is attached hereto. If any references listed herein are in a language other than English, said foreign search report is submitted in satisfaction of the requirements of 37 C.F.R. 1.98(a)(3). Unless a translation accompanies this Statement, no written English-language translation of any non-English language document, or portion thereof, listed herein, is within the possession custody or control of, or is readily available to any individual designated in 37 C.F.R. 1.56(c).

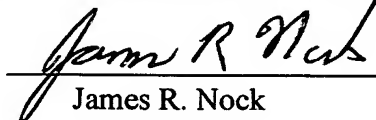
This Information Disclosure Statement is being filed under 37 C.F.R. 1.97(c) before a final action or notice of allowance. No filing fee is required because each item of information contained herein was cited for the first time in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement (certification provided below).

Respectfully submitted,

By 
James R. Nock
Attorney Reg. No. 42,937
Telephone: 1-507-253-4661
Fax: 1-507-253-2382

CERTIFICATION

I hereby certify that each item of information contained herein was cited for the first time in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Statement.

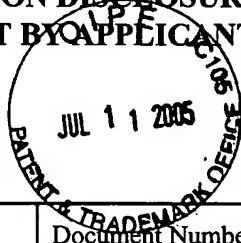

James R. Nock

July 7, 2005
Date

PTO/SB/08A

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

Sheet 1 of 2



Application Number.: 10/767,039
 Filing Date: January 29, 2004
 First Named Inventor: Toshiharu Furukawa
 Art Unit: 2811
 Examiner Name: Unassigned
 Attorney Docket Number.: ROC920030272US1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number Number - Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns or Lines Where Relevant Passages or Figs. Appear
		US - 2002/0001905 A1	01-03-2002	Choi et al.	
		US - 2003/0132461 A1	07-17-2003	Roesner et al.	
		US -			
		US -			
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		US -			

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	Foreign Patent Document Country ³ - Number ⁴ - Kind Code ⁵ Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns or Lines Where Relevant Passages or Figs. Appear	T ⁶
		WO 2004/040668 A	05-13-2004			
		WO 2004/040616 A	05-13-2004			
		WO 2004/105140 A	12-02-2004			
		EP 1420414 A	05-19-2004			

Examiner Signature		Date Considered	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3).

⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language translation is attached.

PTO/SB/08A

Application Number.: 10/767,039Filing Date: January 29, 2004**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**First Named Inventor: Toshiharu FurukawaArt Unit: 2811Examiner Name: Unassigned

Sheet 2 of 2

Attorney Docket Number.: ROC920030272US1**OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS**

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and or country where published.	T ²
		G. S. DUESBERG et al., "Large-Scale Integration of Carbon Nanotubes Into Silicon Based Microelectronics," Proceedings of the SPIE, Bellingham, VA, Vol. 5118, May 21, 2003	

Examiner Signature		Date Considered	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3).

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